

Docket No. 249223US2CONT/ims



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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yoshiharu OOI, et al.

SERIAL NO: 10/784,714

GAU: 2871

FILED: February 24, 2004

EXAMINER: D. Y. CHUNG

FOR: MULTI-LAYER DIFFRACTION TYPE POLARIZER AND LIQUID CRYSTAL ELEMENT

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references cited in the attached European Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☒ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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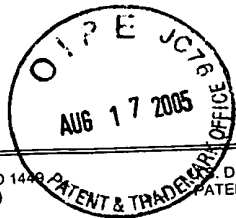
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Form PTO 1449 (Modified)		DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249223US2CONT		SERIAL NO. 10/784,714	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yoshiharu OOI, et al.		GROUP 2871	
				FILING DATE February 24, 2004			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,245,471	09/14/1993	Shinji IWATSUKA, et al.			
	AB	5,914,811	06/22/1999	Yansong CHEN, et al.			
	AC	5,739,952	04/14/1998	Tadashi TAKEDA, et al.			
	AD						
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	6-27320	02/04/1994	JAPAN (with English Abstract)			X
	AP	2000-249831	09/14/2000	JAPAN (with English Abstract)			X
	AQ	2-165023	06/26/1990	JAPAN (with English Abstract)			X
	AR	11-84320	03/26/1999	JAPAN (with English Abstract)			X
	AS	62-289804	12/16/1987	JAPAN (with English Abstract)			X
	AT	11-352326	12/24/1999	JAPAN (with English Abstract)			X
	AU	0 390 610 A2	10/03/1990	EUROPE			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Patent Abstracts of Japan, JP 03-031803, February 12, 1991					
	AX	Derwent Publications, Database WPI, AN 1999-291791, XP-002335464, JP 11-095027, April 9, 1999					
	AY	Patent Abstracts of Japan, JP 2000-347028, December 15, 2000					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							